# **ON Semiconductor**



### FINAL PRODUCT/PROCESS CHANGE NOTIFICATION Generic Copy

Issue Date 27-Oct-2006

SUBJECT: ON Semiconductor Final Product/Process Change Notification #15665

TITLE: Final PCN for Qualification of QFN 0.75 mm package thickness (1.2 x 1mm to 8x8mm, 6 to 52LD) at ON Seremban

PROPOSED FIRST SHIP DATE: 27-Dec-2006

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Assembly and Test Site

AFFECTED PRODUCT DIVISION(S): ON Semiconductor

### FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

 Contact your local ON Semiconductor Sales Office or:

 Edwin Soto
 Edwin.Soto@onsemi.com

 Steven Black
 s.black@onsemi.com

SAMPLES: Contact your local ON Semiconductor Sales Office

#### ADDITIONAL RELIABILITY DATA: Available Contact your local ON Semiconductor Sales Office or Laura.Rivers@onsemi.com

### NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 60 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

## **DESCRIPTION AND PURPOSE:**

This is a Final Product Change Notice to IPCN 15174 available at <u>www.onsemi.com</u> to make customers aware that the ON Semiconductor facility in Seremban, Malaysia is being qualified as a manufacturing source for the ON WQFN packages.

ON Semiconductor, Seremban will provide assembly for COL packages: WQFN1826-16L, WQFN1418-10L, WQFN3010-12L & WQFN1012-6L for Analog, Logic, Discrete, TMOS, and High Frequency products and QFN (DFN2020-6L) uCool Packaged MOSFET products. Testing of these products will be performed by ON Semiconductor Seremban, Malaysia facility.

The affected QFN packages are being qualified to run specific devices that are currently processed in NSEB, Thailand. This is not a transfer but a capacity expansion.

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RELIABILITY DATA SUMMARY:		
Test PC	Conditions 24 hours bake@125C+ 168hr, 85C/85%RH+ 3X IR @ 260 °C +1flux immersion + alcohol + DI H2O rinse.	<b>Results (Rej / SS)</b> 0/84, 0/84, 0/84
AC - PC	121°C/100% RH/15psig Post PC Electrical 96 Hrs	0/84, 0/84, 0/84 0/84, 0/84, 0/84
TC – PC	Ta=-65/+150deg.C, Air to air, Dwell = 10 min. Post PC Electrical 500 Cycles	0/84, 0/84, 0/84 0/84, 0/84, 0/84
HTSL	Ta=131deg.C 1008 Hrs	0/84, 0/84, 0/84
HAST	Ta=131deg.C, 85% RH/18.8psig 96 Hrs	0/84, 0/84, 0/84
RSH	Ta=260deg.C	0/35, 0/35, 0/35

### ELECTRICAL CHARACTERISTIC SUMMARY:

All product performance meets current datasheet specifications. Data is available upon request.

# CHANGED PART IDENTIFICATION:

Part traceability to manufacturing site will follow standard SOP. Parts with a date code of 0642 or greater may be manufactured at either site.

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# **AFFECTED DEVICE LIST:**

## PART

NLAS3799BLMNR2G NLAS3799BMNR2G NLAS3799LMNR2G NLAS3799MNR2G NLAS4717EPMTR2G NLAS5123MNR2G NLAS5223BLMNR2G NLAS5223BMNR2G NLAS5223LMNR2G NLAS5223MNR2G NLAS9134MTR2G NLAS9431MTR2G NLASB3157MTR2G NTLJD3115PT1G NTLJD3115PTAG NTLJD4116NT1G NTLJF3117PT1G NTLJF4156NT1G NTLJF4156NTAG NTLJS3113PT1G NTLJS4159NT1G